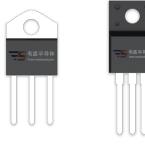


#### **DESCRIPTION:**

With high ability to withstand the shock loading of large current, BTB20-800BW series triacs provide high dv/dt rate with strong resistance to electromagnetic interface. With high commutation performances, 3 quadrants products especially recommended for use on inductive load.



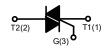


P TO-220F



Symbol	Value	Unit
I <sub>T(RMS)</sub>	20	А
VDRM /VRRM	600/800/1200	V





TO-220A

#### **ABSOLUTE MAXIMUM RATINGS**

Parameter		Symbol	Value	Unit
Storage junction temperature range		T <sub>stg</sub>	-40-150	$^{\circ}\mathbb{C}$
Operating junction temperature range		Tj	-40-125	$^{\circ}$ C
Repetitive peak off-state voltage (T <sub>j</sub> =25℃)		V <sub>DRM</sub>	600/800/1200	V
Repetitive peak reverse voltage (T <sub>j</sub> =25℃)		$V_{RRM}$	600/800/1200	V
Non repetitive surge peak Off-state voltage		V <sub>DSM</sub>	V <sub>DRM</sub> +100	V
Non repetitive peak reverse voltage		Vrsm	V <sub>RRM</sub> +100	V
RMS on-state current	TO-220A(Ins) (Tc=70°C)		20	A
	TO-220A(Non-Ins) (Tc=90℃)	I <sub>T(RMS)</sub>		
	TO-220F(Ins) (T <sub>C</sub> =65℃)	. ( 2)		
	TO-3P(Ins) (T <sub>C</sub> =105°C)			



Non repetitive surge peak on-state current (full cycle, F=50Hz)	I <sub>TSM</sub>	200	А
I <sup>2</sup> t value for fusing (tp=10ms)	l <sup>2</sup> t	200	A <sup>2</sup> s
Critical rate of rise of on-state current $(I_G = 2 \times I_{GT})$	dl/dt	100	A/µs
Peak gate current	I <sub>GM</sub>	4	Α
Average gate power dissipation	P <sub>G(AV)</sub>	1	W
Peak gate power	P <sub>GM</sub>	10	W

# **ELECTRICAL CHARACTERISTICS** (T<sub>j</sub>=25°C unless otherwise specified)

## 3 Quadrants

Symbol	Test Condition	Quadrant		Va	lue	Unit
				BW	CW	Ullit
Ідт	V <sub>D</sub> =12V R <sub>L</sub> =33Ω	I - II -III	MAX	50	35	mA
V <sub>G</sub> T		I - II -III	MAX	1	.3	V
V <sub>GD</sub>	$V_D = V_{DRM} T_j = 125$ °C RL = 3.3KΩ	I - II -III	MIN	0.2		V
I <sub>L</sub> I <sub>G</sub> =1.2I <sub>GT</sub>	1 -4 01	I -III	MAX	70	60	mA
	IG = 1.2IGT	II	IVIAA	90	70	IIIA
lн	I <sub>T</sub> =100mA		MAX	60	50	mA
dV/dt	V <sub>D</sub> =2/3V <sub>DRM</sub> Gate Open T <sub>j</sub> =125℃		MIN	1000	500	V/µs

## 4 Quadrants

Symbol	Test Condition	Quadrant		Value	Unit
I <sub>GT</sub>	V <sub>D</sub> =12V R <sub>L</sub> =33Ω	I - II -III	MAX	50	mA
		IV		70	
V <sub>G</sub> T		ALL	MAX	1.3	V
V <sub>GD</sub>	$V_D = V_{DRM} T_j = 125$ °C $R_L = 3.3$ ΚΩ	ALL	MIN	0.2	V
IL	I <sub>G</sub> =1.2I <sub>GT</sub>	I -III-IV	MAX	70	mΛ
		II	IVIAA	90	mA
I <sub>H</sub>	I <sub>T</sub> =100mA		MAX	60	mA
dV/dt	V <sub>D</sub> =2/3V <sub>DRM</sub> Gate Open T <sub>j</sub> =125℃		MIN	500	V/µs

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### **STATIC CHARACTERISTICS**

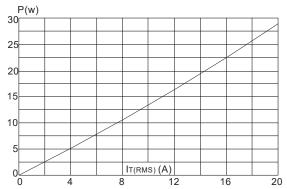
Symbol	Parameter		Value(MAX)	Unit
V <sub>TM</sub>	I <sub>тм</sub> =28A tp=380µs	T <sub>j</sub> =25℃	1.5	V
IDRM	V <sub>D</sub> =V <sub>DRM</sub> V <sub>R</sub> =V <sub>RRM</sub>	T <sub>j</sub> =25℃	5	μA
I <sub>RRM</sub>		T <sub>j</sub> =125℃	2.5	mA

#### THERMAL RESISTANCES

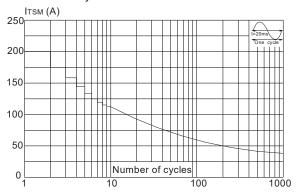
Symbol	Parameter		Value	Unit	
R <sub>th(j-c)</sub>	junction to case(AC)	TO-220A(Ins)	1.9		
		TO-220A(Non-Ins) 1.1		°C /\\	
		TO-220F(Ins)	2.1	°C/W	
		TO-3P	0.7		



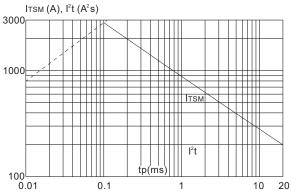
**FIG.1** Maximum power dissipation versus RMS on-state current



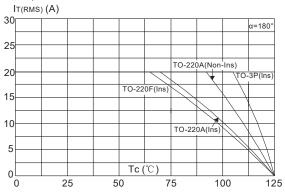
**FIG.3:** Surge peak on-state current versus number of cycles



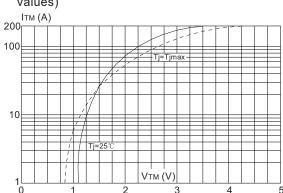
**FIG.5:** Non-repetitive surge peak on-state current for a sinusoidal pulse with width tp<20ms, and corresponging value of  $l^2t$  (dl/dt < 100A/ $\mu$ s)



**FIG.2:** RMS on-state current versus case temperature



**FIG.4:** On-state characteristics (maximum values)



**FIG.6:** Relative variations of gate trigger current, holding current and latching current versus junction temperature

